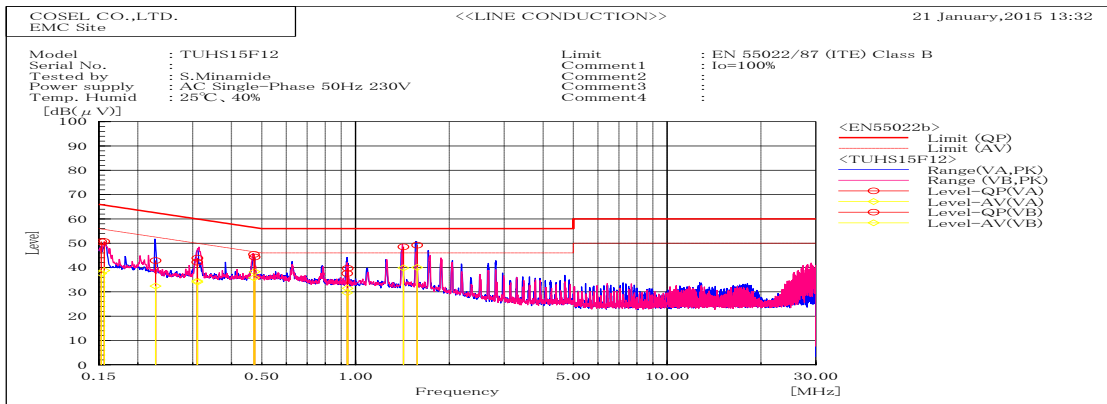
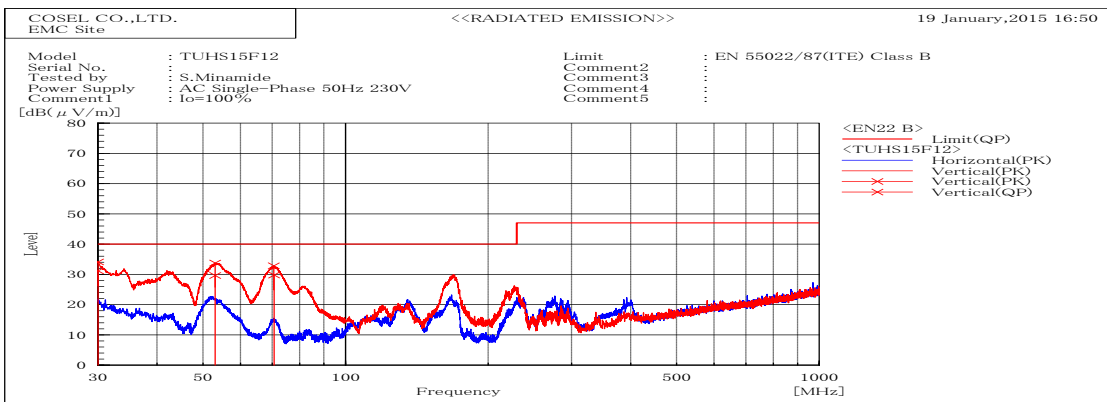


<b>DATA SHEET</b>		Date	26-Feb-15
Model	TUHS15F12	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide



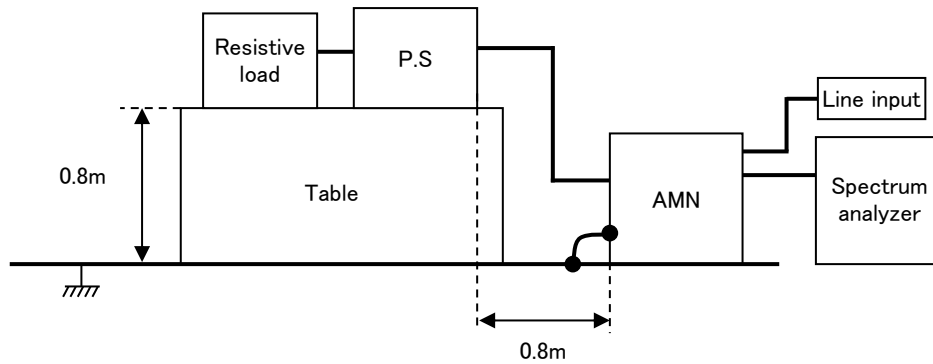
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB(1/m)	Level dB(uV/m)		Limit dB(uV/m)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.1527		VB	30.3	17.2	20.3	50.6	37.5	65.9	55.9	15.3	18.4	Pass	
0.15618		VA	30.4	18.5	20.3	50.7	38.8	65.7	55.7	15	16.9	Pass	
0.22802		VA	22.7	12.2	20.2	42.9	32.4	62.5	52.5	19.6	20.1	Pass	
0.31031		VA	22	14.2	20.2	42.2	34.4	60	50	17.8	15.6	Pass	
0.31095		VB	23.7	13.9	20.1	43.8	34	59.9	49.9	16.1	15.9	Pass	
0.4724		VB	25.3	15.7	20.1	45.4	35.8	56.5	46.5	11.1	10.7	Pass	
0.47444		VA	24.2	18.1	20.1	44.3	38.2	56.4	46.4	12.1	8.2	Pass	
0.94069		VA	17.4	9.4	20.2	37.6	29.6	56	46	18.4	16.4	Pass	
0.94392		VB	19.5	11.2	20.2	39.7	31.4	56	46	16.3	14.6	Pass	
1.42503		VB	28.3	19.6	20.2	48.5	39.8	56	46	7.5	6.2	Pass	
1.576		VA	28.9	19.7	20.3	49.2	40	56	46	6.8	6	Pass	



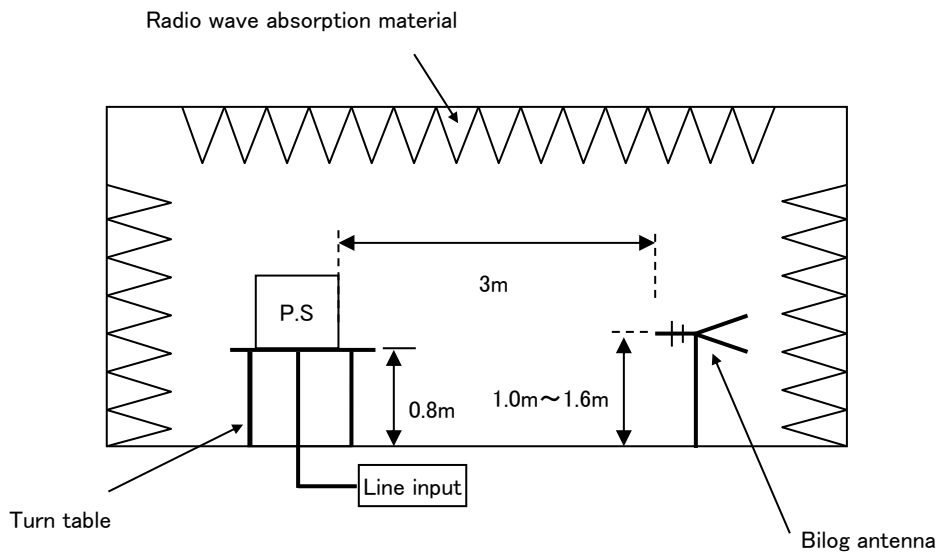
Frequency MHz	Polarization	Stability	Reading dB(uV)	Factor dB(1/m)	Level dB(uV/m)	Limit dB(uV/m)	Margin dB	Pass/Fail	Remark
			QP		QP	QP			
30.025	V	Stable	44.7	-13.5	31.2	40	8.8	Pass	
53.058	V	Stable	53.4	-23.8	29.6	40	10.4	Pass	
70.67	V	Stable	50.4	-20.6	29.8	40	10.2	Pass	

DATA SHEET		Date	26-Feb-15
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide

### 1. Line conduction



### 2. Radiated emission



## Conditions

Test: EMI

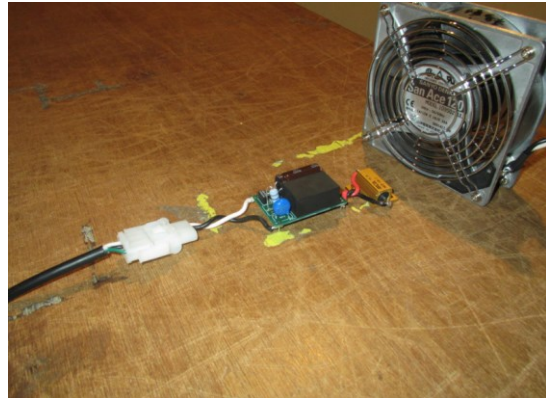
Model Name: TUHS15F□□

○ Photographs of Test Set-Up

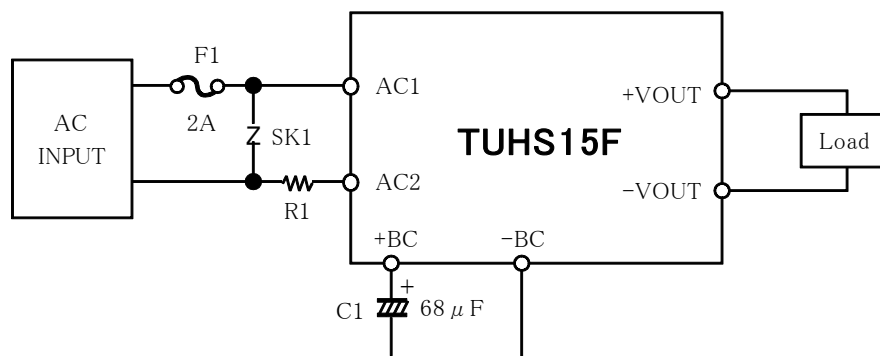
### LINE CONDUCTION



### RADIATED EMISSION



○ Test circuit



F1: SLT250V2A (Nippon Seisen)

R1: CW3CJ (KOA)

SK1: S10K385E2K1 (TDK EPCOS)

2A

10Ω

Fig.1 Testing circuitry